


File 8/26/03

<b>FORM HDP-1449 (Based on Form PTO-1449)</b>  <b>PATENT AND TRADEMARK OFFICE</b> <b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)  Sheet 1 of 1	<b>ATTORNEY DOCKET No.</b>	<b>SERIAL No.</b>
	9319S-000224/DVB	to be assigned
	<b>APPLICANT</b>	
	Takeshi Hagiwara	
	<b>FILING DATE</b>	<b>GROUP</b>
	Herewith	2871

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	JN	5,717,475A	2/1998	Kamio et al	349/147	
2.		6,052,169	4/2000	Kim	349/148	
3.		2001/0033264 A1	10/25/2001	Ishii		
4.	JN	6,456,279	9/24/2002	Kubo et al		

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.	JN	JP361059	3/1986	Japan		
2.		2000-0015775	3/15/2000	Korea		
3.	JN	2000-0030026	5/25/2000	Korea		

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
Ref. Desig.	Examiner's Initials	
1.	JN	Examination report from corresponding Korean application.

<b>Examiner:</b> 	<b>Date Considered:</b> 4/3/04
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<b>PATENT AND TRADEMARK OFFICE</b> <b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary) Sheet 1 of 1		9319S-000224/DVB	10/649,581
		APPLICANT	
		Takeshi Hagiwara	
		FILING DATE	GROUP
		August 26, 2003	2871

### U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

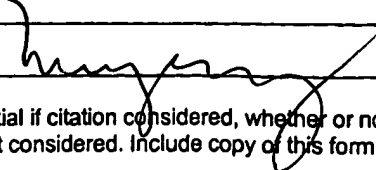
### FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes	No
1.	HN	WO00/28373	5/18/2000	PCT		X	
2.	HN	53-49964		Japan		X	
3.	HN	2000-56294	2/25/2000	Japan		X	
4.	HN	57-101883	6/24/1982	Japan		X	
5.	HN	11-288001	10/19/1999	Japan		X	

### OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	HN	Communication from Japan re: counterpart application.
2.	HN	Patent Abstracts of Japan 2000-056294
3.	HN	Patent Abstracts of Japan 11-288001

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Examiner:  Date Considered: July 29/04

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**PATENT AND TRADEMARK OFFICE  
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Sheet 1 of 1

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9319S-000224/DVB

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**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes No	
1.	JN	62-196626	8/31/1987	Japan		X	
2.	JN	02-287433	11/27/1990	Japan		X	
3.	JN	03-167527	7/19/1991	Japan		X	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
1.	JN	Communication from Japan Patent Office re: counterpart application.

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